

**Homework Assignment #4**

Due by online submission Wednesday 2/15/2017 (Thursday at 9am)

1. You have a PMOS-input common source amplifier with an NMOS load driving a capacitive load. The output is biased at mid-rail. How do  $I_D$ ,  $g_m$ ,  $r_o$ ,  $A_{v0}$ ,  $w_p$ ,  $w_u$ , input capacitance, and output swing change if you
  - a. double the width of both devices
  - b. double the width and length of both devices
  - c. double  $V_{ov}$  in both devices
2. Problem 5, Fa09 Midterm 1.
3. Using the process parameters below, design a common source amplifier with a low-frequency gain of at least 50, and a unity-gain bandwidth of 1.6 GHz while driving a 200fF load. You need an output swing of at least 1V. Make a table of  $W$ ,  $L$ ,  $I_D$ ,  $V_{ov}$ ,  $g_m$ ,  $r_o$ , for each device, and of  $A_{v0}$ ,  $w_p$ ,  $w_u$ , input capacitance, and output swing for the amplifier. You may assume the quadratic model for both FETs, but keep  $V_{ov}$  greater than 100mV. Clearly indicate "picks".
  - a. Is the quadratic model likely to be accurate for the bias conditions of your amplifier?
  - b. If you wanted to minimize power consumption, how would your design change?
  - c. If you wanted to minimize input capacitance, how would your design change?

Process Parameters:  $C_{ox}=5\text{fF}/\mu\text{m}^2$ ,  $C'_{ol}=0.2\text{fF}/\mu\text{m}$ ,  $\mu_n C_{ox}=200\mu\text{A}/\text{V}^2$ ,  $\mu_p C_{ox}=100\mu\text{A}/\text{V}^2$ ,  $\lambda=(0.1\mu\text{m}/L)/(1\text{V})$ ,  $-V_{tp}=V_{tn}=0.5\text{V}$ ,  $V_{DD}=2\text{V}$

4. With  $|V_{ds}|=1\text{V}$ , use Cadence in our 90nm process to simulate  $I_d$  vs  $V_{gs}$  from 0 to  $V_{DD}=1\text{V}$  for both N and P transistors with  $W/L=1\mu/100\text{n}$  and  $W/L=10\mu/1\mu$ . (Both are 10/1 aspect ratio, one is short channel, one is long channel).
  - a. Plot all of the currents. Do the short channel devices look like our velocity saturation model? Do the long channel devices look quadratic? Perhaps over some range of  $V_{gs}$ ?
  - b. For the short channel devices, estimate  $C_{ox}V_{scl}$  and  $V_{th}$
  - c. Plot  $\sqrt{I_d}$  for the long channel devices (click on the calculator icon to do waveform math). Estimate  $\mu C_{ox}$  and  $V_{th}$  for both N and P devices.
  - d. Plot  $\log_{10}(I_d)$  for all devices. Estimate  $n$ .
  - e. Plot  $g_m$  for all devices (there's a "deriv" function). What do you expect to see for short channel and long channel devices? In what range of  $V_{gs}$  does the  $g_m$  of these devices look like it comes from a quadratic or velocity saturated model? Is that consistent with any critical E-field?
  - f. Plot  $g_m/I_d$  for all devices. In what device, and at what operating condition, do you get the most bang for the buck (most  $g_m$  per mA)?
5. For the same devices as above, simulate  $I_{DS}$  vs  $V_{DS}$  from 0 to  $V_{DD}=1\text{V}$  with  $V_{GS}=0.5\text{V}$ .
  - a. Plot all four currents on the same plot. Is there a clear transition from triode to saturation? Is it the same for short and long channel? Estimate  $V_A$  for each device.
  - b. For each device, plot  $I_{ds}$  and  $r_o$  on the same plot.
  - c. For each device, find the max  $r_o$ , and the range of  $V_{ds}$  for which  $r_o > r_{o,max}/2$
  - d. Is  $(1+\lambda V_{ds})/(\lambda I_d)$  a good model for output resistance for any/some/all of these devices? Over what range of voltages?
6. [ee240A] Come up with a model for hand analysis for transistors of length 0.1 to 1 $\mu\text{m}$  that gives your best guess at  $g_m$  and  $r_o$  as a function of geometry and bias. How accurate is it in terms of percent error?